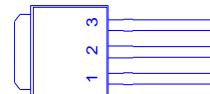
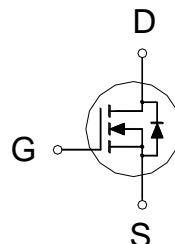


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P0165EI
TO-251
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
650V	10.6Ω	1A


 1. GATE
 2. DRAIN
 3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	650	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	1	A
		0.7	
Pulsed Drain Current ^{1, 2}	I_{DM}	1.8	A
Avalanche Current ³	I_{AS}	0.5	
Avalanche Energy ³	E_{AS}	1.25	mJ
Power Dissipation	P_D	37	W
		15	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	3.4	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed³ $V_{DD} = 50\text{V}$, $L = 10\text{mH}$, starting $T_J = 25^\circ\text{C}$

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	650			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2	3.1	4	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			± 100	nA
Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 650\text{V}, V_{\text{GS}} = 0\text{V}, T_C = 25^\circ\text{C}$			1	
		$V_{\text{DS}} = 520\text{V}, V_{\text{GS}} = 0\text{V}, T_C = 100^\circ\text{C}$			10	μA
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 0.5\text{A}$		8.5	10.6	Ω
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 15\text{V}, I_D = 0.5\text{A}$		2		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		161		pF
Output Capacitance	C_{oss}			33		
Reverse Transfer Capacitance	C_{rss}			10		
Total Gate Charge ²	Q_g	$V_{\text{DD}} = 520\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}$		3.4		nC
Gate-Source Charge ²	Q_{gs}			0.7		
Gate-Drain Charge ²	Q_{gd}			0.8		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current ³	I_S				1	A
Forward Voltage ¹	V_{SD}	$I_F = 1\text{A}, V_{\text{GS}} = 0\text{V}$			1	V
Reverse Recovery Time	t_{rr}	$I_F = 1\text{A}, dI_F/dt = 100\text{A} / \mu\text{s}$		253		nS
Reverse Recovery Charge	Q_{rr}			0.64		uC

¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

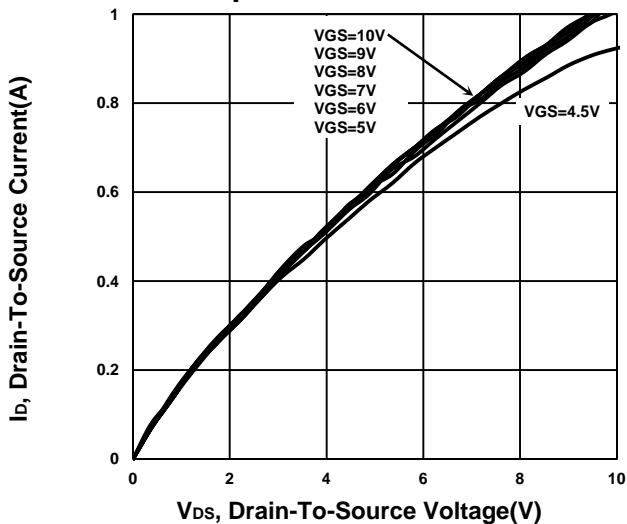
³Pulse width limited by maximum junction temperature.

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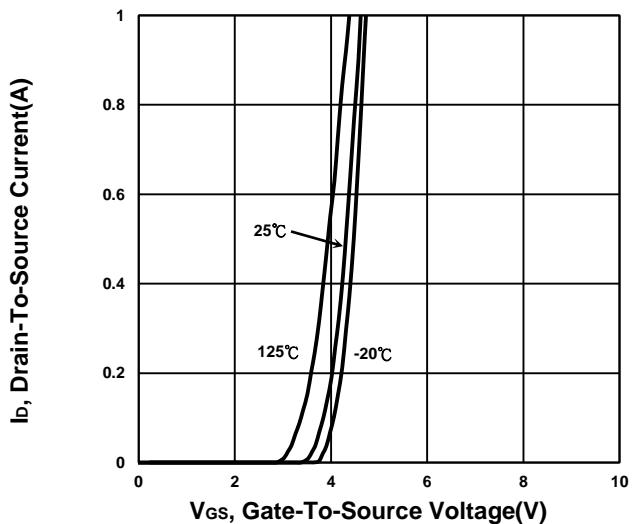
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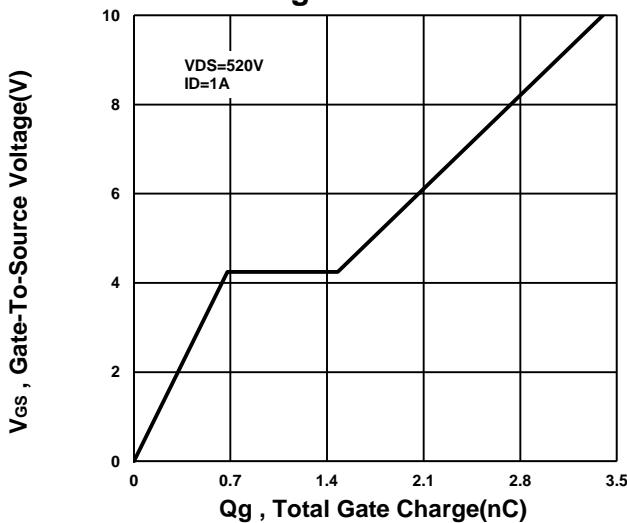
Output Characteristics



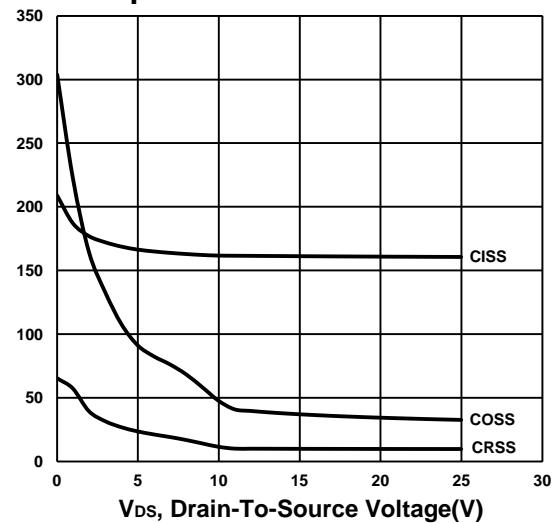
Transfer Characteristics



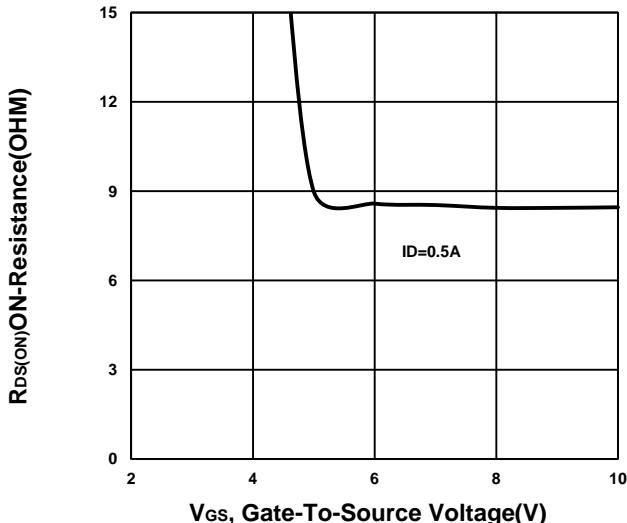
Gate charge Characteristics



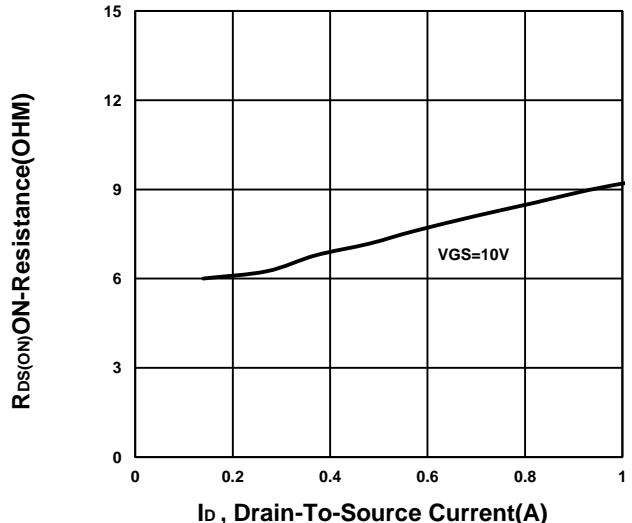
Capacitance Characteristic



On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current



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